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| <b>LIST OF DOCUMENTS CITED BY APPLICANT</b><br>(Use several sheets if necessary) |  |                                |                          |
| APPLICANT<br>M. Toshiyuki, Y. Masami, H. Yoshihiro                               |  |                                |                          |
| FILING DATE<br>November 2, 2000  |  |                                | GROUP<br>2858 2829       |

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| EXAMINER<br>INITIAL |    | DOCUMENT NUMBER | DATE       | NAME             | CLASS | SUBCLASS | FILING DATE IF<br>APPROPRIATE |
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| JP                  | AB | 4,473,796       | 9/25/1984  | Nankivil         |       |          |                               |
| JP                  | AC | 4,498,044       | 2/5/1985   | Horn             |       |          |                               |
| JP                  | AD | 5,416,470       | 5/18/1995  | Tanaka et al.    |       |          |                               |
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| JP                  | AF | 5,808,516       | 9/15/1998  | Barber           |       |          |                               |
| JP                  | AG | 5,886,529       | 3/23/1999  | Wakamatsu        |       |          |                               |
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| EXAMINER<br>INITIAL |    | DOCUMENT NUMBER | DATE       | COUNTRY          | CLASS | SUBCLASS | TRANSLATION |    |
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| EXAMINER:   | T.R. L. | CITE CONSIDERED: 5/22/02  |
| *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |         |   |

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